

UTILITY
SERIAL
NUMBER
08/799506 PATENT DATE
PATENT
NUMBER

SERIAL NUMBER 08/799,506	FILING DATE 02/12/97	CLASS 117	SUBCLASS 84	EXAMINER 2842 2822 W/17-651
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SHUNPEI YAMAZAKI, TOKYO, JAPAN; HIROYUKI SHIMADA, KANAGAWA-KEN, JAPAN;
AKIRA TAKENOUCHI, KANAGAWA-KEN, JAPAN; YASUHIKO TAKEMURA, KANAGAWA-KEN,
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CONTINUING DATA

VERIFIED THIS APPLN IS A CON OF 08/330,797 10/28/94 ABN
BY WHICH IS A CIP OF 08/160,909 12/03/93

FOREIGN/PCT APPLICATIONS **** * * * *

VERIFIED JAPAN 35-301172 11/05/93
JAPAN 6-100642 04/13/94

CPA

Foreign priority claimed 35 USC 119 conditions met	<input type="checkbox"/> yes <input type="checkbox"/> no <input checked="" type="checkbox"/> yes <input type="checkbox"/> no	AS FILED	STATE OR COUNTRY	Sheets DWGS.	TOTAL CLAIMS	INDEP. CLAIMS	FILING FEE RECEIVED	ATTORNEY'S DOCKET NO.
Verified and Acknowledged	Examiner's initials		JPX	10	31	8	\$1,412.00	0756-15-0

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IN-CIRCUIT, VIRGINIA 24390
METHOD FOR PROCESSING SEMICONDUCTOR DEVICE APPARATUS FOR PROCESSING A
SEMICONDUCTOR AND APPARATUS FOR PROCESSING SEMICONDUCTOR DEVICE

U.S. DEPT. OF COMM./PAT. & TM—PTO-4361 (Rev. 12-94)